


<b>Search Notes</b>  	<b>Application/Control No.</b>  10578762	<b>Applicant(s)/Patent Under Reexamination</b>  TAN ET AL.
	<b>Examiner</b>  Bashaw, Heidi M	<b>Art Unit</b>  4138

<b>SEARCHED</b>			
<b>Class</b>	<b>Subclass</b>	<b>Date</b>	<b>Examiner</b>
433	10-11	10.24.2006	HMB

<b>SEARCH NOTES</b>		
<b>Search Notes</b>	<b>Date</b>	<b>Examiner</b>
W/ Wilson on above search	10.24.2007	HMB

<b>INTERFERENCE SEARCH</b>			
<b>Class</b>	<b>Subclass</b>	<b>Date</b>	<b>Examiner</b>